

Notice of References Cited

Application/Control No.

10/524,715

Applicant(s)/Patent Under
Reexamination
LEE ET AL.

Examiner

HAI V. NGUYEN

Art Unit

2618

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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*	B	US-2004/0105402 A1	06-2004	Yi et al.	370/312
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NON-PATENT DOCUMENTS

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